







**CSD18534KCS** SLPS383C - SEPTEMBER 2012 - REVISED MARCH 2024

## CSD18534KCS 60V N-Channel NexFET™ Power MOSFET

#### 1 Features

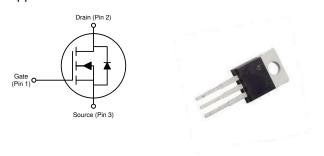
- Ultra-low  $\mathbf{Q}_{g}$  and  $\mathbf{Q}_{gd}$  Low thermal resistance
- Avalanche rated
- Logic level
- Pb-Free terminal plating
- RoHS compliant
- Halogen free
- TO-220 plastic package

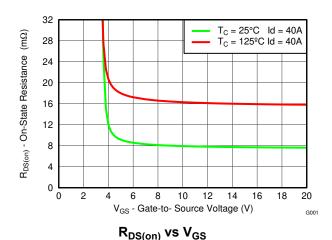
## 2 Applications

- DC-DC conversion
- Secondary side synchronous rectifier
- Motor control

### 3 Description

This 7.6m $\Omega$ , 60V TO-220 NexFET<sup>TM</sup> power MOSFET is designed to minimize losses in power conversion applications.





**Product Summary** 

T <sub>A</sub> = 25°	С	TYPICAL VA	UNIT	
V <sub>DS</sub>	Drain-to-Source Voltage 60			
Qg	Gate Charge Total (10V) 19			
Q <sub>gd</sub>	Gate Charge Gate-to-Drain	3.1	nC	
R <sub>DS(on)</sub> Drain-to-Source On-Resistance		V <sub>GS</sub> = 4.5V 10.2		mΩ
R <sub>DS(on)</sub>	Dialii-to-Source Oii-Resistance	V <sub>GS</sub> = 10V	7.6	mΩ
V <sub>GS(th)</sub>	Threshold Voltage	1.9		V

## Ordering Information<sup>(1)</sup>

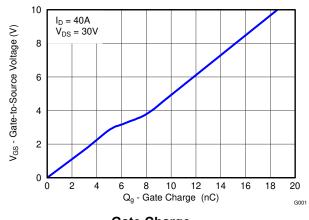
Device	Package	Media	Qty	Ship
CSD18534KCS	TO-220 Plastic Package	Tube	50	Tube

For all available packages, see the orderable addendum at the end of the data sheet.

#### **Absolute Maximum Ratings**

T <sub>A</sub> = 2	25°C	VALUE	UNIT
V <sub>DS</sub>	Drain-to-Source Voltage	60	V
V <sub>GS</sub>	Gate-to-Source Voltage	±20	V
	Continuous Drain Current (Package limited)	100	
I <sub>D</sub>	Continuous Drain Current (Silicon limited), T <sub>C</sub> = 25°C	73	Α
	Continuous Drain Current (Silicon limited), T <sub>C</sub> = 100°C	52	
I <sub>DM</sub>	Pulsed Drain Current (1)	164	Α
P <sub>D</sub>	Power Dissipation	107	W
T <sub>J</sub> , T <sub>stg</sub>	Operating Junction and Storage Temperature Range	-55 to 175	°C
E <sub>AS</sub>	Avalanche Energy, single pulse $I_D$ = 38A, L = 0.1mH, $R_G$ = 25 $\Omega$	72	mJ

#### Max R<sub>θJC</sub> = 1.3°C/W, pulse duration ≤100μs, duty cycle ≤1%



**Gate Charge** 



## **Table of Contents**

1 Features1	5.1 Third-Party Products Disclaimer7
2 Applications 1	5.2 Receiving Notification of Documentation Updates7
3 Description1	5.3 Support Resources7
4 Specifications3	
4.1 Electrical Characteristics3	5.5 Electrostatic Discharge Caution7
4.2 Thermal Information3	5.6 Glossary7
4.3 Typical MOSFET Characteristics4	6 Revision History8
5 Device and Documentation Support7	7 Mechanical, Packaging, and Orderable Information 9

## 4 Specifications

## **4.1 Electrical Characteristics**

T<sub>A</sub> = 25°C unless otherwise stated

PARAMETER	TEST CONDITIONS	MIN TYP	MAX	UNIT				
STATIC CHARACTERISTICS								
Drain-to-Source Voltage	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA	60		V				
Drain-to-Source Leakage Current	V <sub>GS</sub> = 0V, V <sub>DS</sub> = 48V		1	μA				
Gate-to-Source Leakage Current	V <sub>DS</sub> = 0V, V <sub>GS</sub> = 20V		100	nA				
Gate-to-Source Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	1.5 1.9	2.3	V				
R <sub>DS(on)</sub> Drain-to-Source On-Resistance	V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 40A	10.2	13.3	mΩ				
Drain-to-Source On-Resistance	V <sub>GS</sub> = 10V, I <sub>D</sub> = 40A	7.6	9.5	mΩ				
Transconductance	V <sub>DS</sub> = 30V, I <sub>D</sub> = 40A	100		S				
IC CHARACTERISTICS		•						
Input Capacitance		1500	1880	pF				
Output Capacitance	$V_{GS} = 0V, V_{DS} = 30V, f = 1MHz$	164	205	pF				
Reverse Transfer Capacitance		5.0	6.5	pF				
Series Gate Resistance		1.5	3.0	Ω				
Gate Charge Total (4.5V)		9.3	12	nC				
Gate Charge Total (10V)		19	24	nC				
Gate Charge Gate-to-Drain	$V_{DS} = 30V, I_{D} = 40A$	3.1		nC				
Gate Charge Gate-to-Source		4.8		nC				
Gate Charge at V <sub>th</sub>		3.3		nC				
Output Charge	V <sub>DS</sub> = 30V, V <sub>GS</sub> = 0V	18		nC				
Turn On Delay Time		4.2		ns				
Rise Time	V <sub>DS</sub> = 30V, V <sub>GS</sub> = 10V,	4.8		ns				
Turn Off Delay Time	$I_{DS} = 40A$ , $R_G = 0\Omega$	10.4		ns				
Fall Time		2.4		ns				
CHARACTERISTICS		•						
Diode Forward Voltage	I <sub>SD</sub> = 40A, V <sub>GS</sub> = 0V	0.8	1	V				
Reverse Recovery Charge	V <sub>DS</sub> = 30V, I <sub>F</sub> = 40A,	68		nC				
Reverse Recovery Time	di/dt = 300A/µs	49		ns				
	Drain-to-Source Voltage Drain-to-Source Leakage Current Gate-to-Source Leakage Current Gate-to-Source Threshold Voltage Drain-to-Source On-Resistance Transconductance IC CHARACTERISTICS Input Capacitance Output Capacitance Reverse Transfer Capacitance Series Gate Resistance Gate Charge Total (4.5V) Gate Charge Total (10V) Gate Charge Gate-to-Drain Gate Charge Gate-to-Source Gate Charge at V <sub>th</sub> Output Charge Turn On Delay Time Rise Time Turn Off Delay Time Fall Time CHARACTERISTICS Diode Forward Voltage Reverse Recovery Charge	CHARACTERISTICS         Drain-to-Source Voltage $V_{GS} = 0V$ , $I_D = 250\mu$ A         Drain-to-Source Leakage Current $V_{DS} = 0V$ , $V_{DS} = 48V$ Gate-to-Source Threshold Voltage $V_{DS} = V_{GS}$ , $I_D = 250\mu$ A         Drain-to-Source On-Resistance $V_{DS} = V_{GS}$ , $I_D = 250\mu$ A         Transconductance $V_{CS} = 4.5V$ , $I_D = 40A$ Transconductance $V_{DS} = 30V$ , $I_D = 40A$ IC CHARACTERISTICS         Input Capacitance $V_{CS} = 0V$ , $V_{DS} = 30V$ , $I_D = 40A$ Reverse Transfer Capacitance $V_{CS} = 0V$ , $V_{DS} = 30V$ , $V_{DS} = 30$	CHARACTERISTICS           Drain-to-Source Voltage         V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA         60           Drain-to-Source Leakage Current         V <sub>GS</sub> = 0V, V <sub>DS</sub> = 48V           Gate-to-Source Leakage Current         V <sub>DS</sub> = 0V, V <sub>DS</sub> = 20V           Gate-to-Source Threshold Voltage         V <sub>DS</sub> = 0V, V <sub>DS</sub> = 250μA         1.5           Drain-to-Source On-Resistance         V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 40A         10.2           V <sub>DS</sub> = 30V, I <sub>D</sub> = 40A         7.6           Transconductance         V <sub>DS</sub> = 30V, I <sub>D</sub> = 40A         100           Input Capacitance         1500           Output Capacitance         V <sub>GS</sub> = 0V, V <sub>DS</sub> = 30V, I = 1MHz         164           Reverse Transfer Capacitance         5.0           Series Gate Resistance         1.5         9.3           Gate Charge Total (4.5V)         9.3         9.3           Gate Charge Total (10V)         9.3         1.5           Gate Charge Gate-to-Drain         V <sub>DS</sub> = 30V, I <sub>D</sub> = 40A         3.1           Gate Charge at V <sub>Ih</sub> 3.3         3.3           Output Charge         V <sub>DS</sub> = 30V, V <sub>GS</sub> = 0V         18           Turn On Delay Time         4.2         4.2           Rise Time         V <sub>DS</sub> = 30V, V <sub>GS</sub> = 10V, V <sub>DS</sub> = 10V, V <sub>DS</sub> = 10V, V <sub>DS</sub> = 40A, V <sub>DS</sub> = 0V         4.8     <	CHARACTERISTICS           Drain-to-Source Voltage         V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA         60           Drain-to-Source Leakage Current         V <sub>GS</sub> = 0V, V <sub>DS</sub> = 48V         1           Gate-to-Source Leakage Current         V <sub>DS</sub> = 0V, V <sub>DS</sub> = 20V         100           Gate-to-Source Threshold Voltage         V <sub>DS</sub> = 20V, V <sub>DS</sub> = 250µA         1.5         1.9         2.3           Drain-to-Source On-Resistance         V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 40A         7.6         9.5           Transconductance         V <sub>DS</sub> = 30V, I <sub>D</sub> = 40A         100         100           Input Capacitance         1500         1880           CC CHARACTERISTICS         1500         1880           Input Capacitance         V <sub>GS</sub> = 0V, V <sub>DS</sub> = 30V, I = 1MHz         164         205           Reverse Transfer Capacitance         5.0         6.5           Reverse Transfer Capacitance         5.0         6.5           Series Gate Resistance         1.5         3.0           Gate Charge Total (4.5V)         9.3         12           Gate Charge Total (10V)         19         24           Gate Charge Gate-to-Drain         4.8         3.3           Gate Charge at V <sub>th</sub> 3.3         3.3           Output Charge         V <sub>DS</sub> = 30				

### **4.2 Thermal Information**

T<sub>A</sub> = 25°C unless otherwise stated

	THERMAL METRIC	MIN	TYP	MAX	UNIT
$R_{\theta JC}$	Junction-to-Case Thermal Resistance			1.3	°C/W
$R_{\theta JA}$	Junction-to-Ambient Thermal Resistance			62	C/VV

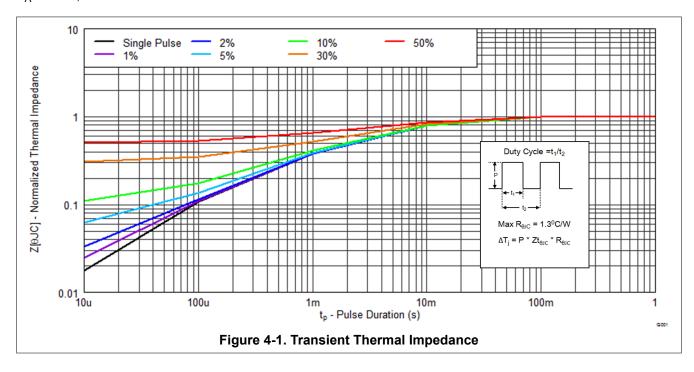
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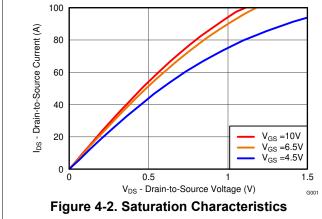
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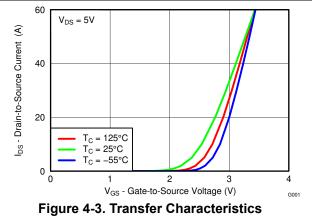


# **4.3 Typical MOSFET Characteristics**

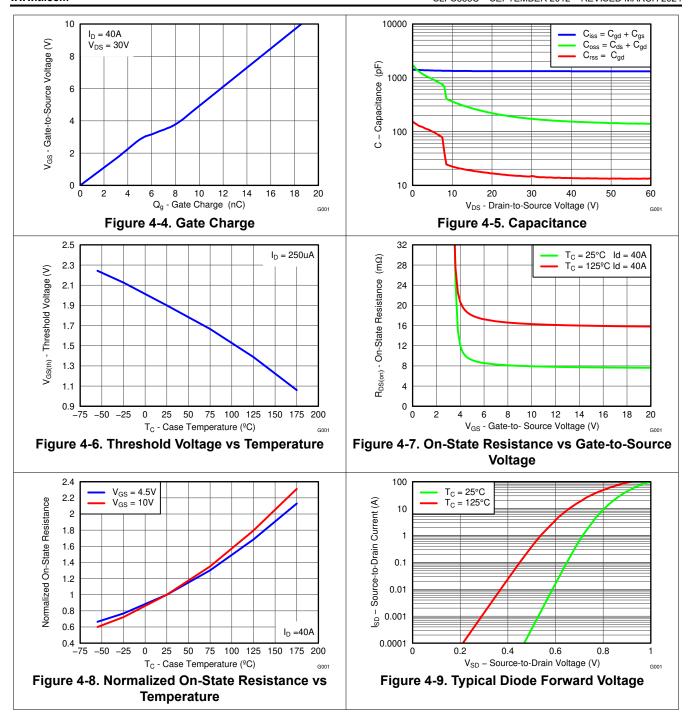
 $T_A = 25$ °C, unless otherwise stated



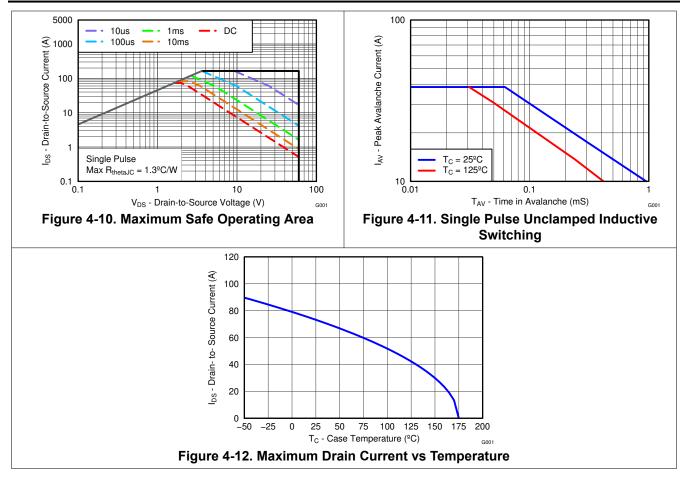












## **5 Device and Documentation Support**

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This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

#### 5.6 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

Product Folder Links: CSD18534KCS



# **6 Revision History**

Changes from Revision B (October 2014) to Revision C (March 202	24) Page
Updated the numbering format for tables, figures, and cross-referen	
Changes from Revision A (April 2014) to Revision B (October 2014	l) Page
Increased I <sub>DM</sub> to 164 A	.,
Updated pulsed current conditions	1
• Updated Figure 4-1 from a normalized $R_{\theta JA}$ to a normalized $R_{\theta JC}$ cu	
Updated the SOA in Figure 4-10	
Changes from Revision A (April 2014) to Revision B (October 2014	l) Page
Increased I <sub>DM</sub> to 164 A	,1
Updated pulsed current conditions	
• Updated Figure 4-1 from a normalized $R_{\theta JA}$ to a normalized $R_{\theta JC}$ cu	
Updated the SOA in Figure 4-10	
Changes from Revision * (September 2012) to Revision A (April 20	14) Page
Updated document title	
Updated description	
· Adjusted currents to reflect higher temperature capability in Absolut	
<ul> <li>Adjusted max power to reflect higher temperature capability in Absorbance</li> </ul>	
<ul> <li>Increased maximum temperature to 175°C in Absolute Maximum Ra</li> </ul>	
Updated Figure 4-6 to extend to 175°C	
Updated Figure 4-8 to extend to 175°C	
Updated Figure 4-12 to extend to 175°C	

Product Folder Links: CSD18534KCS



## 7 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

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#### PACKAGING INFORMATION

Orderable Devi	ice	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
								(6)				
CSD18534KC	S	ACTIVE	TO-220	KCS	3	50	RoHS-Exempt & Green	SN	N / A for Pkg Type	-55 to 175	CSD18534KCS	Samples

(1) The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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# **PACKAGE MATERIALS INFORMATION**

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#### **TUBE**

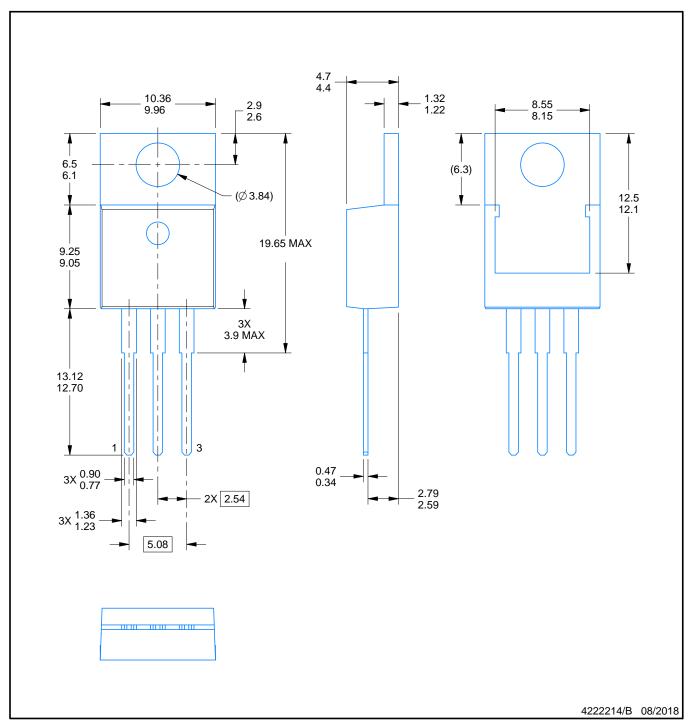


#### \*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
CSD18534KCS	KCS	TO-220	3	50	532	34.1	700	9.6
CSD18534KCS	KCS	TO-220	3	50	532	34.1	700	9.6



TO-220



#### NOTES:

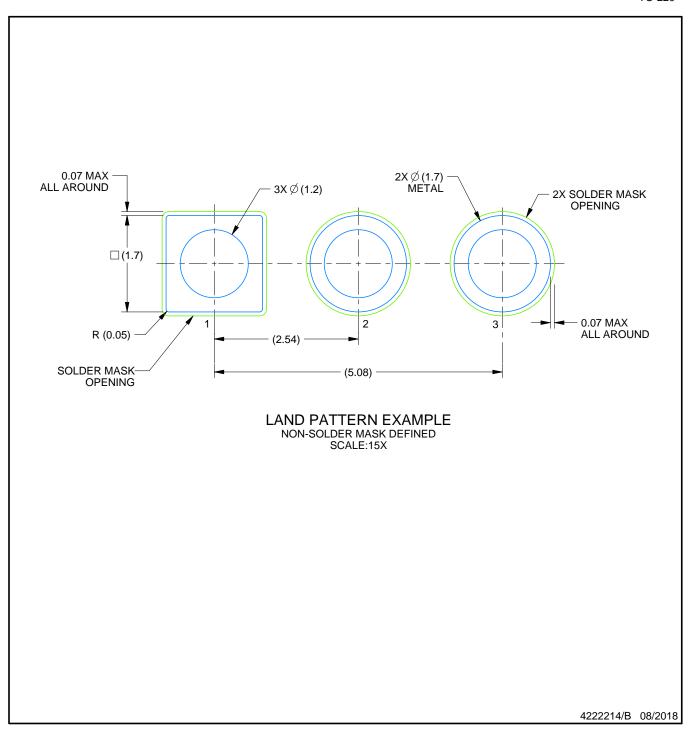
- 1. Dimensions are in millimeters. Any dimension in brackets or parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. Reference JEDEC registration TO-220.



TO-220



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